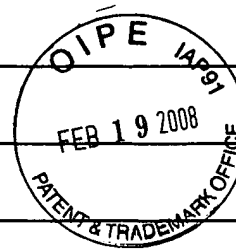


## INFORMATION DISCLOSURE STATEMENT

FORM PTO 1449 (modified)

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Ken-ichi KITAYAMA et al.FILING DATE  
September 11, 2007GROUP  
2627

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6,160,504	12-12-00	Fields et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	BA	0 985 956	3-15-00	Europe			x
	BB	1 093 011	4-18-01	Europe			x
	BC	93/05592	3-18-93	WO			x

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	CA	Supplementary European Search Report issued January 11, 2008 in the European Application No. EP 04-81 8553.
	CB	J.-M. Jeong et al., "All-Optical analog-to-digital and digital-to-analog conversion implemented by a nonlinear fiber interferometer", Optics Communications, North-Holland Publishing Co., Amsterdam, NL, Vol. 91, No. 1/2, July 1, 1992, pages 115-122
	CC	Akihiro Maruta et al., "All-Optical Analog-to-Digital Conversion Utilizing Nonlinear Phenomena in Fiber", Leos 2002, 15 <sup>th</sup> Annual Meeting of the IEEE Lasers & Electro-Optics Society, Glasgow, Scotland, November 11-12, 2002, Annual Meeting of the IEEE Lasers and Electro-Optics Society, New York, NY, IEEE, US, Vol. 1 of 2, November 13, 2002, pages 430-431
	CD	Tsuyoshi Konishi et al., "All-optical analog-to-digital converter by use of self-frequency shifting in fiber and a pulse-shaping technique", Journal of the Optical Society of America B, Vol. 19, No. 11, November 2002, pages 2817-2823
	CE	Paul W. Juodawlkis et al., "Optically Sampled Analog-to-Digital Converters", IEEE Transactions on Microwave Theory and Techniques, IEEE Service Center, Piscataway, NJ, US, Vol. 49, No. 10, October 2001, pages 1840-1853

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.